

TLP2451

1. Applications

- Transistor Inverters
- MOSFET Gate Drivers
- IGBT Gate Drivers
- Induction Cooktop and Home Appliances

2. General

The TLP2451 is a photocoupler in a SO8 package that consists of a GaAlAs infrared light-emitting diode (LED) optically coupled to an integrated high-gain, high-speed photodetector IC chip. It provides guaranteed performance and specifications at temperatures up to 125°C.

The TLP2451 has an internal Faraday shield that provides a guaranteed Common-mode transient immunity of 15 kV/μs. It has a totem-pole output that can both sink and source current. The TLP2451 is ideal for IGBT and power MOSFET gate drive.

3. Features

- (1) Output peak current: ±0.6 A (max)
- (2) Operating temperature: -40 to 125°C
- (3) Supply current: 2 mA (max)
- (4) Supply voltage: 10 to 30 V
- (5) Threshold input current: 5 mA (max)
- (6) Propagation delay time: $t_{pHL}/t_{pLH} = 700$ ns (max)
- (7) Common-mode transient immunity: ±15 kV/μs (min)
- (8) Isolation voltage: 3750 Vrms (min)
- (9) Safety standards

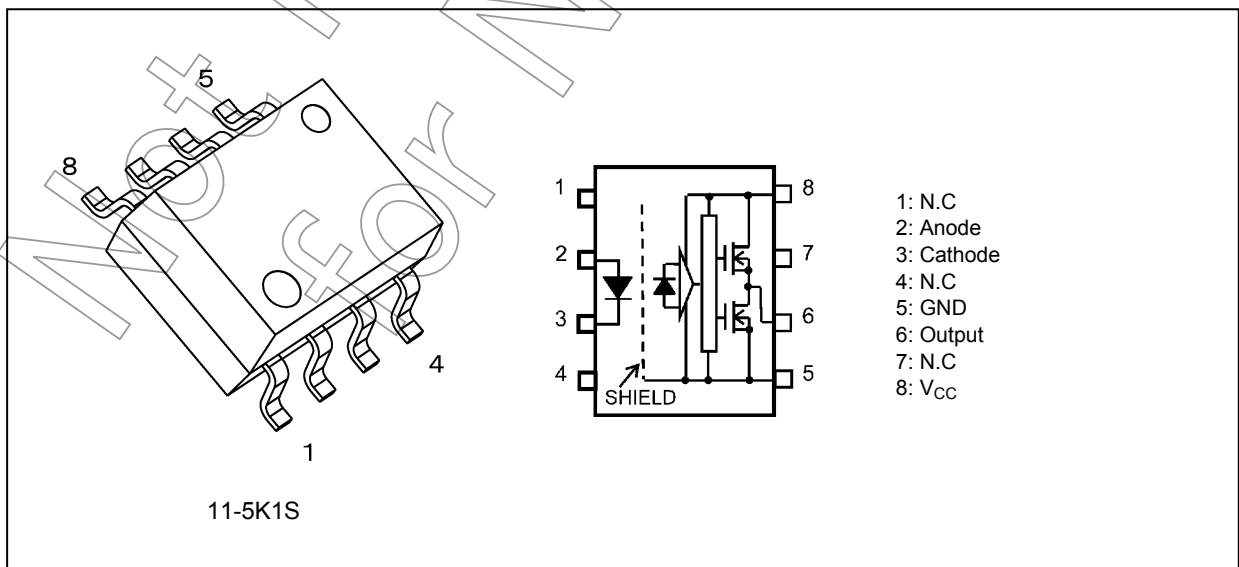
UL-approved: UL1577 (approval pending) File No.E67349

cUL-approved: CSA Component Acceptance Service No.5A (approval pending), File No.E67349

VDE-approved: Option (V4) EN60747-5-2 (approval pending) **(Note)**

Note: When an EN60747-5-2 approved type is needed, please designate the **Option (V4)**.

4. Packaging and Pin Configuration



5. Internal Circuit (Note)

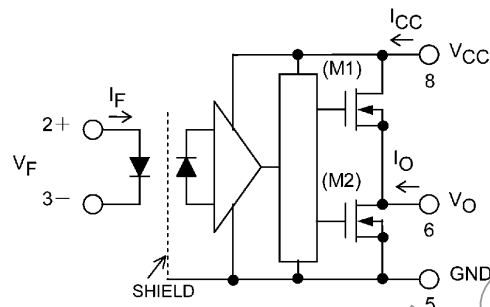


Fig. 5.1 Internal Circuit

Note: A 0.1 μ F bypass capacitor must be connected between pin 8 and pin 5.

6. Principle of Operation

6.1. Truth Table

Input	LED	M1	M2	Output
H	ON	ON	OFF	H
L	OFF	OFF	ON	L

6.2. Mechanical Parameters

Characteristics	Min	Unit
Creepage distances	4.2	mm
Clearance distances	4.2	
Internal isolation thickness		

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7. Absolute Maximum Ratings (Note) (Unless otherwise specified, $T_a = 25^\circ\text{C}$)

	Characteristics	Symbol	Note	Rating	Unit
LED	Input forward current	I_F		25	mA
	Input forward current derating ($T_a \geq 110^\circ\text{C}$)	$\Delta I_F/\Delta T_a$		-0.67	mA/°C
	Input forward current (pulsed)	I_{FP}	(Note 1)	1	A
	Input forward current derating (pulsed) ($T_a \geq 110^\circ\text{C}$)	$\Delta I_{FP}/\Delta T_a$		-25	mA/°C
	Input reverse voltage	V_R		5	V
	Input power dissipation	P_D		40	mW
	Input power dissipation derating ($T_a \geq 110^\circ\text{C}$)	$\Delta P_D/\Delta T_a$		-1.0	mW/°C
Detector	Peak high-level output current ($T_a = -40$ to 125°C)	I_{OPH}	(Note 2)	-0.6	A
	Peak low-level output current ($T_a = -40$ to 125°C)	I_{OPL}	(Note 2)	+0.6	
	Output voltage	V_O		35	V
	Supply voltage	V_{CC}		35	
	Output power dissipation	P_O		160	mW
	Output power dissipation derating ($T_a \geq 110^\circ\text{C}$)	$\Delta P_O/\Delta T_a$		-4.0	mW/°C
Common	Operating temperature	T_{opr}		-40 to 125	°C
	Storage temperature	T_{stg}		-55 to 150	
	Lead soldering temperature (10 s)	T_{sol}	(Note 3)	260	
	Isolation voltage AC, 1 min, R.H. $\leq 60\%$, $T_a = 25^\circ\text{C}$	BV_S	(Note 4)	3750	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Pulse width (PW) $\leq 1 \mu\text{s}$, 300 pps

Note 2: Exponential waveform. Pulse width $\leq 2 \mu\text{s}$, $f \leq 10 \text{ kHz}$

Note 3: $\geq 2 \text{ mm}$ below seating plane.

Note 4: This device is considered as a two-terminal device. Pins 1, 2, 3 and 4 are shorted together, and pins 5, 6, 7 and 8 are shorted together.

8. Recommended Operating Conditions (Note)

Characteristics	Symbol	Note	Min	Typ.	Max	Unit
Input on-state current	$I_{F(ON)}$	(Note 1)	7.5	—	15	mA
Input off-state voltage	$V_{F(OFF)}$		0	—	0.8	V
Supply voltage	V_{CC}	(Note 2)	10	—	30	
Peak high-level output current	I_{OPH}		—	—	-0.2	A
Peak low-level output current	I_{OPL}		—	—	+0.2	
Operating frequency	f	(Note 3)	—	—	25	kHz

Note: The recommended operating conditions are given as a design guide necessary to obtain the intended performance of the device. Each parameter is an independent value. When creating a system design using this device, the electrical characteristics specified in this datasheet should also be considered.

Note: A ceramic capacitor (0.1 μF) should be connected between pin 8 and pin 5 to stabilize the operation of a high-gain linear amplifier. Otherwise, this photocoupler may not switch properly. The bypass capacitor should be placed within 1 cm of each pin.

Note 1: The rise and fall times of the input on-current should be less than 0.5 μs .

Note 2: Denotes the operating range, not the recommended operating condition.

Note 3: Exponential waveform. $I_{OPH} \geq -0.3 \text{ A}$ ($\leq 2.0 \mu\text{s}$), $I_{OPL} \leq 0.3 \text{ A}$ ($\leq 2.0 \mu\text{s}$), $T_a = 125^\circ\text{C}$

9. Electrical Characteristics (Note)
(Unless otherwise specified, $T_a = -40$ to 125°C)

Characteristics	Symbol	Note	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Input forward voltage	V_F			$I_F = 10 \text{ mA}$, $T_a = 25^\circ\text{C}$	1.45	1.55	1.7	V
Input forward voltage temperature coefficient	$\Delta V_F / \Delta T_a$			$I_F = 10 \text{ mA}$	—	-2.0	—	mV/ $^\circ\text{C}$
Input reverse current	I_R			$V_R = 5 \text{ V}$, $T_a = 25^\circ\text{C}$	—	—	10	μA
Input capacitance	C_t			$V = 0 \text{ V}$, $f = 1 \text{ MHz}$, $T_a = 25^\circ\text{C}$	—	60	—	pF
Peak high-level output current	I_{OPH}	(Note 1)	Fig. 12.1.1	$I_F = 5 \text{ mA}$, $V_{CC} = 15 \text{ V}$, $V_{8-6} = 4 \text{ V}$	—	-0.4	-0.2	A
				$I_F = 5 \text{ mA}$, $V_{CC} = 15 \text{ V}$, $V_{8-6} = 10 \text{ V}$	—	—	-0.4	
Peak low-level output current	I_{OPL}	(Note 1)	Fig. 12.1.2	$I_F = 0 \text{ mA}$, $V_{CC} = 15 \text{ V}$, $V_{6-5} = 2 \text{ V}$	0.2	0.5	—	A
				$I_F = 0 \text{ mA}$, $V_{CC} = 15 \text{ V}$, $V_{6-5} = 10 \text{ V}$	0.4	—	—	
High-level output voltage	V_{OH}		Fig. 12.1.3	$I_F = 5 \text{ mA}$, $V_{CC} = 10 \text{ V}$, $I_O = -100 \text{ mA}$	6.0	8.5	—	V
Low-level output voltage	V_{OL}		Fig. 12.1.4	$V_F = 0.8 \text{ V}$, $V_{CC} = 10 \text{ V}$, $I_O = 100 \text{ mA}$	—	0.35	1.0	V
High-level supply current	I_{CCH}		Fig. 12.1.5	$I_F = 10 \text{ mA}$, $V_{CC} = 10$ to 30 V , $V_O = \text{Open}$	—	1.1	2.0	mA
Low-level supply current	I_{CCL}		Fig. 12.1.6	$I_F = 0 \text{ mA}$, $V_{CC} = 10$ to 30 V , $V_O = \text{Open}$	—	1.1	2.0	
Threshold input current (L/H)	I_{FLH}			$V_{CC} = 15 \text{ V}$, $V_O > 1 \text{ V}$	—	1.2	5	V
Threshold input voltage (H/L)	V_{FHL}			$V_{CC} = 15 \text{ V}$, $V_O < 1 \text{ V}$	0.8	—	—	
Supply voltage	V_{CC}			—	10	—	30	V

Note: All typical values are at $T_a = 25^\circ\text{C}$.

Note: This device is designed for low power consumption, making it more sensitive to ESD than its predecessors.

Extra care should be taken in the design of circuitry and pc board implementation to avoid ESD problems.

Note 1: I_O application time $\leq 50 \mu\text{s}$, single pulse.

10. Isolation Characteristics (Unless otherwise specified, $T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Note	Test Conditions	Min	Typ.	Max	Unit
Total capacitance (input to output)	C_S	(Note 1)	$V_S = 0 \text{ V}$, $f = 1 \text{ MHz}$	—	0.8	—	pF
Isolation resistance	R_S	(Note 1)	$V_S = 500 \text{ V}$, R.H. $\leq 60\%$	1×10^{12}	10^{14}	—	Ω
Isolation voltage	BV_S		AC, 1 min	3750	—	—	Vrms
			AC, 1 s, in oil	—	10000	—	
			DC, 1 min, in oil	—	10000	—	Vdc

Note 1: This device is considered as a two-terminal device: Pins 1, 2, 3 and 4 are shorted together, and pins 5, 6, 7 and 8 are shorted together.

11. Switching Characteristics (Note)
 (Unless otherwise specified, $T_a = -40$ to 125°C)

Characteristics	Symbol	Note	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Propagation delay time (L/H)	t_{pLH}	(Note 1)	Fig. 12.1.7	$I_F = 0 \rightarrow 5 \text{ mA}$, $V_{CC} = 30 \text{ V}$, $R_g = 47 \Omega$, $C_g = 3 \text{ nF}$	30	—	700	ns
Propagation delay time (H/L)	t_{pHL}	(Note 1)		$I_F = 5 \rightarrow 0 \text{ mA}$, $V_{CC} = 30 \text{ V}$, $R_g = 47 \Omega$, $C_g = 3 \text{ nF}$	30	—	700	
Rise time	t_r	(Note 1)		$I_F = 0 \rightarrow 5 \text{ mA}$, $V_{CC} = 30 \text{ V}$, $R_g = 47 \Omega$, $C_g = 3 \text{ nF}$	—	50	—	
Fall time	t_f	(Note 1)		$I_F = 5 \rightarrow 0 \text{ mA}$, $V_{CC} = 30 \text{ V}$, $R_g = 47 \Omega$, $C_g = 3 \text{ nF}$	—	50	—	
Pulse width distortion	$ t_{pHL} - t_{pLH} $	(Note 1)		$I_F = 0 \leftrightarrow 5 \text{ mA}$, $V_{CC} = 30 \text{ V}$, $R_g = 47 \Omega$, $C_g = 3 \text{ nF}$	—	—	500	
Common-mode transient immunity at output high	CM_H	(Note 2)	Fig. 12.1.8	$V_{CM} = 1000 \text{ V}_{p-p}$, $I_F = 5 \text{ mA}$, $V_{CC} = 30 \text{ V}$, $T_a = 25^\circ\text{C}$, $V_{O(min)} = 26 \text{ V}$	± 15	± 20	—	kV/ μs
Common-mode transient immunity at output low	CM_L	(Note 3)		$V_{CM} = 1000 \text{ V}_{p-p}$, $I_F = 0 \text{ mA}$, $V_{CC} = 30 \text{ V}$, $T_a = 25^\circ\text{C}$, $V_{O(min)} = 1 \text{ V}$	± 15	± 20	—	

Note: All typical values are at $T_a = 25^\circ\text{C}$.

Note 1: $f = 25 \text{ kHz}$, duty = 50%, input current $t_r = t_f = 5 \text{ ns}$, C_L is approximately 15 pF which includes probe and stray wiring capacitance.

Note 2: CM_H is the maximum rate of rise of the common mode voltage that can be sustained with the output voltage in the logic high state ($V_O > 26 \text{ V}$).

Note 3: CM_L is the maximum rate of fall of the common mode voltage that can be sustained with the output voltage in the logic low state ($V_O < 1 \text{ V}$).

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12. Test Circuits and Characteristics Curves

12.1. Test Circuits

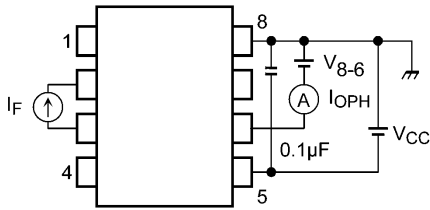


Fig. 12.1.1 I_{OPH} Test Circuit

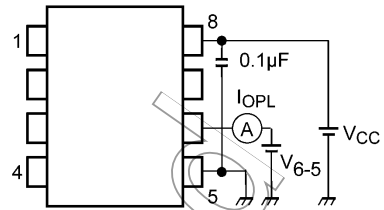
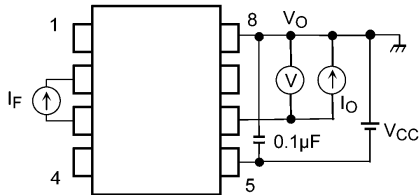


Fig. 12.1.2 I_{OPL} Test Circuit



* $V_{OH} = V_{CC} - V_O$

Fig. 12.1.3 V_{OH} Test Circuit

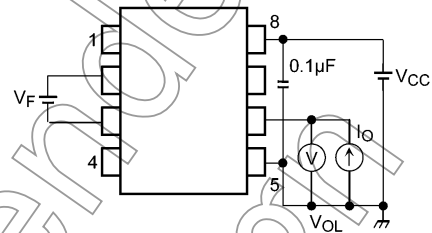


Fig. 12.1.4 V_{OL} Test Circuit

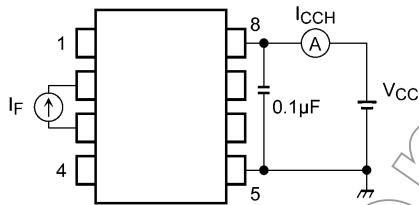


Fig. 12.1.5 I_{CCH} Test Circuit

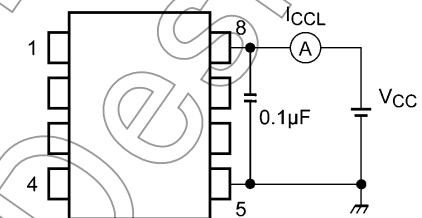


Fig. 12.1.6 I_{CCL} Test Circuit

$I_F = 5 \text{ mA (P.G.)}$
 $(f = 25 \text{ kHz, duty} = 50\%, \text{ less than } t_r = t_f = 5 \text{ ns})$

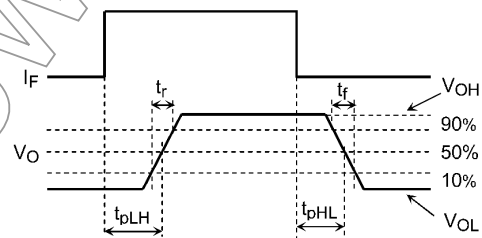
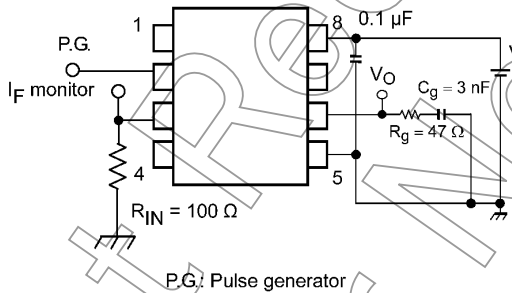
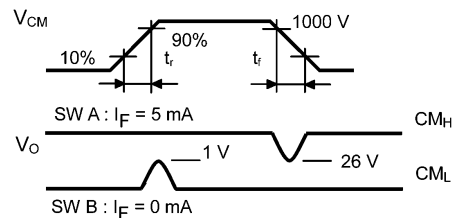
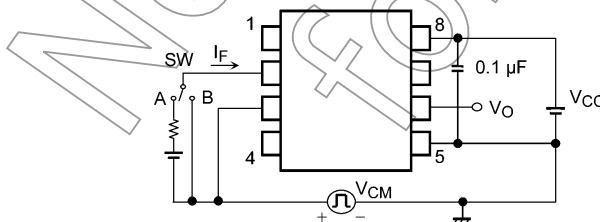


Fig. 12.1.7 Switching Time Test Circuit



$$CM_L = \frac{800(V)}{t_r(\mu S)} \quad CM_H = -\frac{800(V)}{t_f(\mu S)}$$

CM_L (CM_H) is the maximum rate of rise (fall) of the common mode voltage that can be sustained with the output voltage in the low (high) state.

Fig. 12.1.8 Common-Mode Transient Immunity

13. Soldering and Storage

13.1. Precautions for Soldering

The soldering temperature should be controlled as closely as possible to the conditions shown below, irrespective of whether a soldering iron or a reflow soldering method is used.

- When using soldering reflow (See Fig. 13.1.1 and 13.1.2)

Reflow soldering must be performed once or twice.

The mounting should be completed with the interval from the first to the last mountings being 2 weeks.

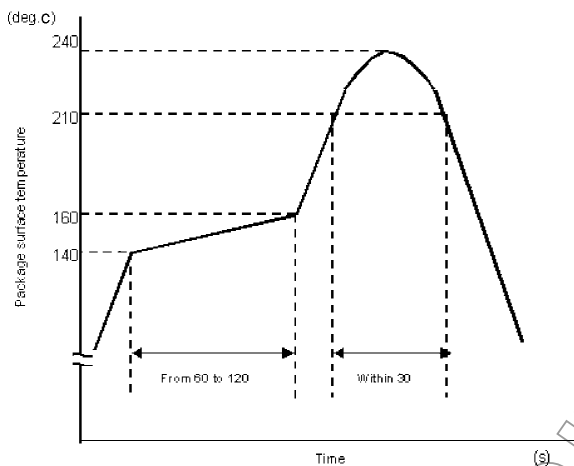


Fig. 13.1.1 An example of a temperature profile when Sn-Pb eutectic solder is used

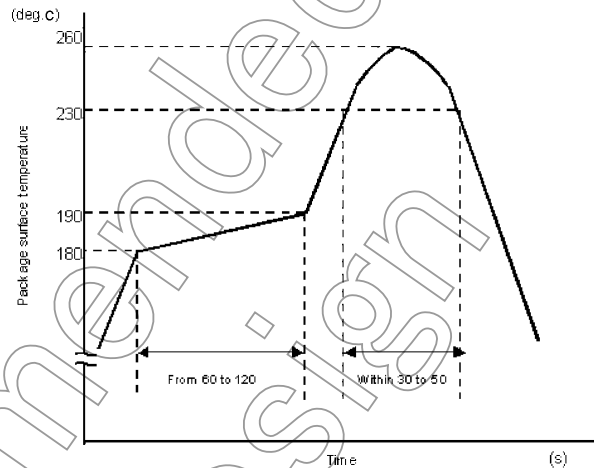


Fig. 13.1.2 An example of a temperature profile when lead(Pb)-free solder is used

- When using soldering flow (Applicable to both eutectic solder and Lead(Pb)-Free solder)
Apply preheating of 150°C for 60 to 120 seconds.
Mounting condition of 260°C within 10 seconds is recommended.
Flow soldering must be performed once.
- When using soldering Iron (Applicable to both eutectic solder and Lead(Pb)-Free solder)
Complete soldering within 10 seconds for lead temperature not exceeding 260°C or within 3 seconds not exceeding 350°C
Heating by soldering iron must be done only once per lead.

13.2. Precautions for General Storage

- Avoid storage locations where devices may be exposed to moisture or direct sunlight.
- Follow the precautions printed on the packing label of the device for transportation and storage.
- Keep the storage location temperature and humidity within a range of 5°C to 35°C and 45% to 75%, respectively.
- Do not store the products in locations with poisonous gases (especially corrosive gases) or in dusty conditions.
- Store the products in locations with minimal temperature fluctuations. Rapid temperature changes during storage can cause condensation, resulting in lead oxidation or corrosion, which will deteriorate the solderability of the leads.
- When restoring devices after removal from their packing, use anti-static containers.
- Do not allow loads to be applied directly to devices while they are in storage.
- If devices have been stored for more than two years under normal storage conditions, it is recommended that you check the leads for ease of soldering prior to use.

14. Land Pattern Dimensions for Reference Only

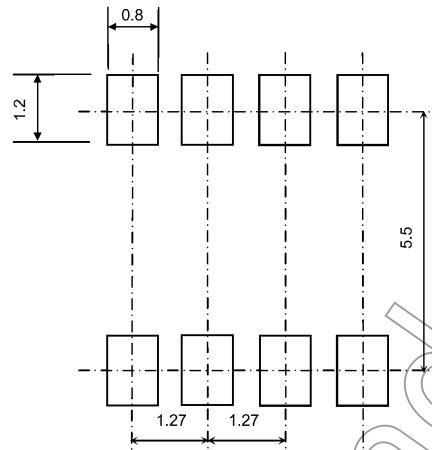


Fig. 14.1 Land Pattern Dimensions for Reference Only (unit: mm)

15. Marking

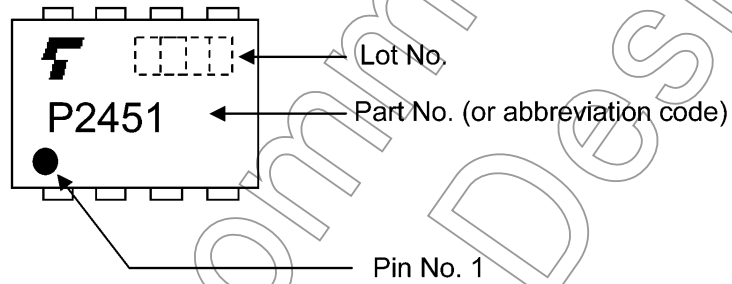


Fig. 15.1 Marking

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16. EN60747-5-2 Option (V4) Specification

- Part number: TLP2451 (**Note**)
- The following part naming conventions are used for the devices that have been qualified according to option (V4) of EN60747.

Example: TLP2451(V4-TP,F)

V4: EN60747 option

TP: Tape type

F: [[G]]/RoHS COMPATIBLE (**Note 1**)

Note: Use TOSHIBA standard type number for safety standard application.

e.g., TLP2451(V4-TP,F) → TLP2451

Note 1: Please contact your TOSHIBA sales representative for details as to environmental matters such as the RoHS compatibility of Product.

RoHS is the Directive 2002/95/EC of the European Parliament and of the Council of 27 January 2003 on the restriction of the use of certain hazardous substances in electrical and electronics equipment.

Description	Symbol	Rating	Unit
Application classification for rated mains voltage ≤ 150Vrms for rated mains voltage ≤ 300Vrms		I-IV I-III	—
Climatic classification		40 / 125 / 21	—
Pollution degree		2	—
Maximum operating insulation voltage	V_{IORM}	565	Vpeak
Input to output test voltage, Method A $V_{pr}=1.5 \times V_{IORM}$, type and sample test $t_p=10s$, partial discharge<5pC	V_{pr}	850	Vpeak
Input to output test voltage, Method B $V_{pr}=1.875 \times V_{IORM}$, 100% production test $t_p=1s$, partial discharge<5pC	V_{pr}	1060	Vpeak
Highest permissible overvoltage (transient overvoltage, $t_{pr}=60s$)	V_{TR}	6000	Vpeak
Safety limiting values (max. permissible ratings in case of fault, also refer to thermal derating curve) current (input current I_F , $P_{so}=0$) power (output or total power dissipation) temperature	I_{si} P_{so} T_s	250 400 150	mA mW °C
Insulation resistance $V_{IO}=500V, T_a=T_s$	R_{si}	$\geq 10^9$	Ω

Fig. 16.1 EN60747 Insulation Characteristics

Minimum creepage distance	Cr	4.0 mm
Minimum clearance	Cl	4.0 mm
Minimum insulation thickness	ti	—
Comparative tracking index	CTI	175

Fig. 16.2 Insulation Related Specifications (Note)

Note: If a printed circuit is incorporated, the creepage distance and clearance may be reduced below this value. (e. g., at a standard distance between soldering eye centers of 3.5 mm). If this is not permissible, the user shall take suitable measures.

Note: This photocoupler is suitable for safe electrical isolation only within the safety limit data. Maintenance of the safety data shall be ensured by means of protective circuits.

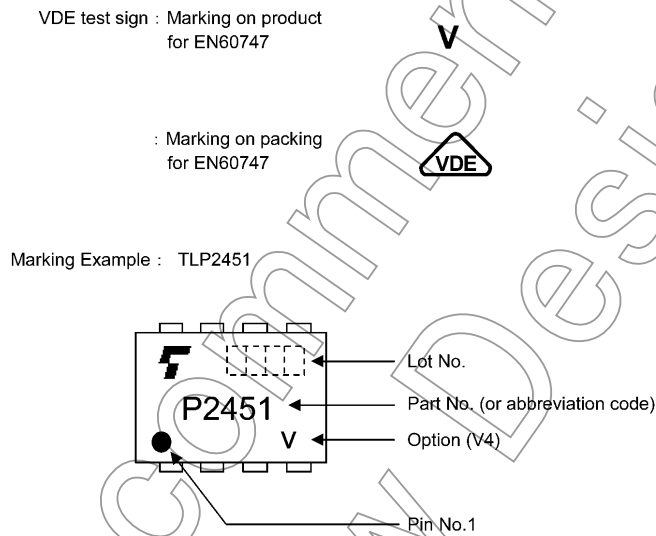


Fig. 16.3 Marking Example (Note)

Note: The above marking is applied to the photocouplers that have been qualified according to option (V4) of EN60747.

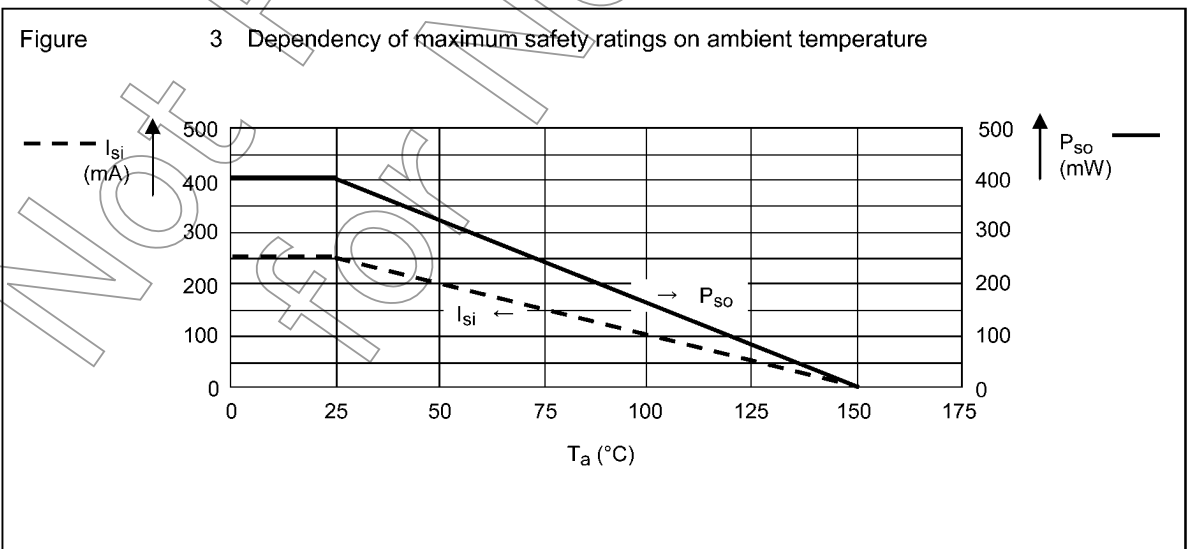
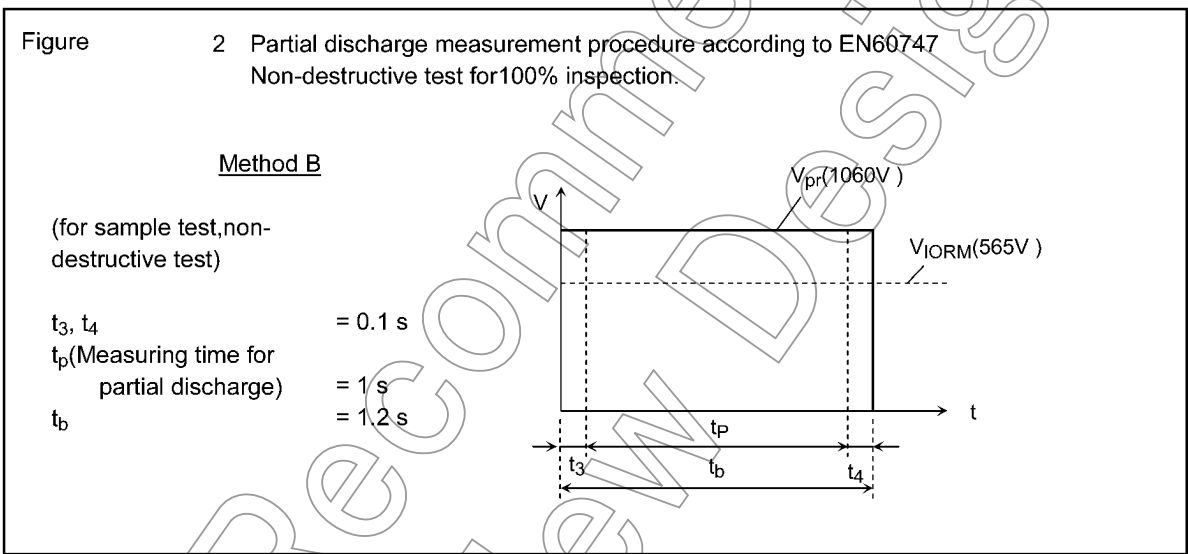
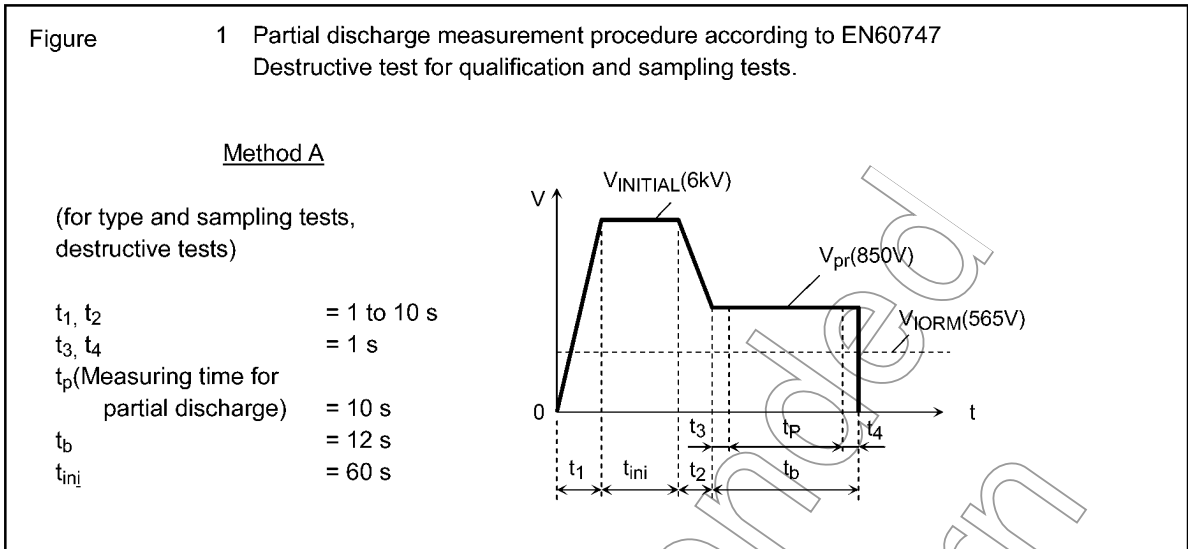
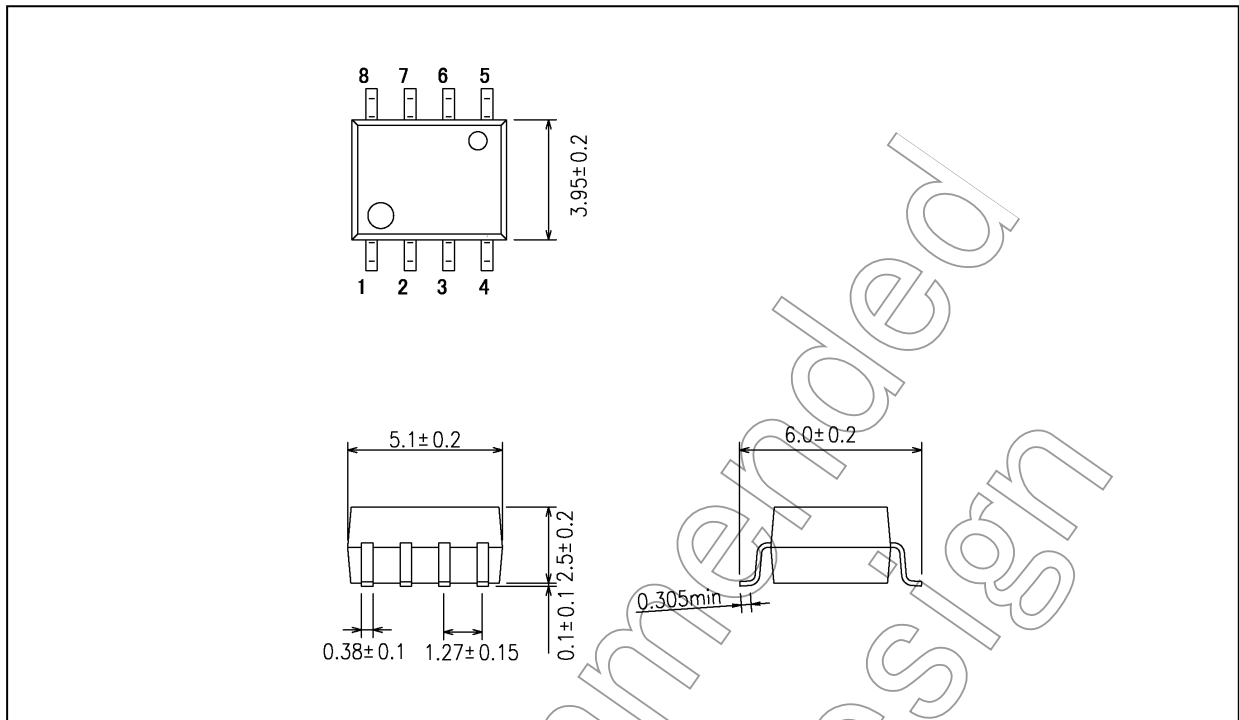


Fig. 16.4 Measurement Procedure

Package Dimensions

Unit: mm



Weight: 0.11 g (typ.)

Package Name(s)
TOSHIBA: 11-5K1S

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